

J.A. Woollam VASE Ellipsometer

Overview

The Variable Angle Spectroscopic Ellipsometer is capable of high accuracy measurement of various optical properties of thin film materials. It is primarily used to measure the film thickness and/or optical constants from a thin film. Analysis is simplest for single-layer films deposited on a Si substrate, although analysis of multilayer specimens is also reasonably straightforward.

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LMACS Name	VASE Ellipsometer
Confluence Label	vase-vb-400
Process Area	CHARACTERIZATION
Model	VASE VB-400
Vendor	J.A. Woollam
Team	Josh Perkins Devin Fortier Peng Li

System Features

- 300–1700 nm spectral range
- Reflection and transmission ellipsometry
- Reflectance (R) intensity
- Transmission (T) intensity
- Depolarization, scatterometry, Mueller-matrix
- RAE + autoretarder equipped

Documents

Operating Procedure	J.A. Woollam VASE Ellipsometer SOP
Hazard Assessment	J.A. Woollam VASE Ellipsometer HA

Related Documents

- J.A. Woollam VASE Ellipsometer (Equipment)
 - equipment
 - characterization
 - requires-update
 - vase-ellipsometer
 - vase-vb-400
 - materials-analysis
 - vase
- J.A. Woollam VASE Ellipsometer SOP (Equipment)
 - sop
 - characterization
 - vase
 - equipment
- Toolbox (software) (nanoFAB Knowledge Base)
 - application-note
 - toolbox
 - calculator
 - vase
 - tystar
 - oxidation
 - sputtering
 - filmetrics-f50-uv
 - tube7
 - kjlc-cms18-sputter-bob
 - kjlc-cms18-sputter-doug

- aja
- [VASE VB-400 Ellipsometer SOP & HA Listing \(Equipment\)](#)
 - procedure
 - in-progress
 - vase-vb-400
- [VASE Ellipsometer - Controller Upgrade \(Equipment\)](#)
 - deployment-log
 - vase-ellipsometer